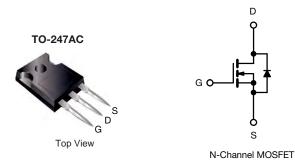


## IXTH30N60P-VB Datasheet

## N-Channel 650 V (D-S) Super Junction MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650				
R <sub>DS(on)</sub> (Ω) at 25 °C	$V_{GS} = 10 V$	0.19			
Q <sub>g</sub> max. (nC)	106				
Q <sub>gs</sub> (nC)	14				
Q <sub>gd</sub> (nC)	33				
Configuration	Single				



### **FEATURES**

- Reduced t<sub>rr</sub>, Q<sub>rr</sub>, and I<sub>RRM</sub>
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q<sub>rr</sub>
- Ultra low gate charge (Q<sub>q</sub>)

Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Telecommunications
  - Server and telecom power supplies
- Lighting
  - High-intensity discharge (HID)
- Fluorescent ballast lighting
- Consumer and computing - ATX power supplies
- Industrial
  - Welding
  - Battery chargers
- Renewable energy
- Solar (PV inverters)
- Switch mode power supplies (SMPS)

<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_C = 25 \text{ °C}$ , unless otherwise noted)								
PARAMETER			SYMBOL	LIMIT	UNIT			
Drain-Source Voltage			V <sub>DS</sub>	650	v			
Gate-Source Voltage			V <sub>GS</sub>	± 30	v			
Continuous Drain Current (T <sub>J</sub> = 150 °C)	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25 \ ^{\circ}{\rm C}$ $T_{\rm C} = 100 \ ^{\circ}{\rm C}$	I <sub>D</sub>	20				
		T <sub>C</sub> = 100 °C		13	А			
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	53				
Linear Derating Factor				1.7	W/°C			
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	367	mJ			
Maximum Power Dissipation			PD	208	W			
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C			
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		dV/dt	37	- V/ns			
Reverse Diode dV/dt <sup>d</sup>			av/at	31	v/ns			
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s			300	°C			

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD} = 50$  V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 5.1 A.

c. 1.6 mm from case.

d.  $I_{SD} \leq I_D$ , dl/dt = 100 A/µs, starting  $T_J$  = 25 °C.



PARAMETER SYMBOL TYP. MAX. UNIT   Maximum Junction-to-To-Maient $R_{th,A}$ - 62 °C/W   SPECIFICATIONS (T_j = 25 °C, unless otherwise noted) PARAMETER SYMBOL TST CONDITIONS MIN. TYP. MAX. UNIT   SPECIFICATIONS (T_j = 25 °C, unless otherwise noted) PARAMETER SYMBOL TEST CONDITIONS MIN. TYP. MAX. UNIT   Static Drain-Source Breakdown Voltage VDS VGS = 100 /L, D = 250 µA 650 - - V/C   Gate-Source Threshold Voltage (N) VGS(H) Reference to 25 °C, Lg = 1 mA - 0.67 - V/C   Gate-Source Threshold Voltage (N) VGS(H) VGS = 20 V - - 1 µA   Zero Gate Voltage Drain Current VDS = 520 V, VGS = 0 V - - 1 µA   Type VDS = 520 V, VGS = 0 V, T_D = 125 °C - - 1 µA   Drain-Source On-State Resistance RDS(m) VDS = 10 V ID = 11 A - 0.0 - 16	THERMAL RESISTANCE RAT	NGS							
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	PARAMETER	SYMBOL	TYP. MAX.				UNIT		
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 62						
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$	Maximum Junction-to-Case (Drain)		- 0.5				- °C/W		
$\begin{array}{ c c c c c c c c c c c c c c c c c c c$									
Static Vois Vois Vois Vois Vois $V_{0S} = 0 V$ , $l_0 = 250 \mu A$ 650 - - V/rocham   Gate-Source Dreshold Voltage (N) Vois Wiss Pois	<b>SPECIFICATIONS</b> (T <sub>J</sub> = 25 °C, u	unless otherw	ise noted)						
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	PARAMETER	SYMBOL	TES	T CONDIT	IONS	MIN.	TYP.	MAX.	UNIT
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Static					1	<b>I</b>	1	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub>	= 0 V, I <sub>D</sub> =	250 µA	650	-	-	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C,	I <sub>D</sub> = 1 mA	-	0.67	-	V/°C
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> =	250 µA	2	-	4	V
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Onto Course Lookana			$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Leakage	IGSS				-	-	± 1	μA
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Zara Cata Valtaga Drain Current	1	V <sub>DS</sub> =			-	-	1	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Zero Gate voltage Drain Current	IDSS	V <sub>DS</sub> = 520 \	/, V <sub>GS</sub> = 0 <sup>v</sup>	V, T <sub>J</sub> = 125 °C	-	-	500	μA
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	I	<sub>D</sub> = 11 A	-	0.19	-	Ω
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Forward Transconductance		V <sub>DS</sub>	= 30 V, I <sub>D</sub>	= 11 A	-	7.0	-	S
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Dynamic	•				•			
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Input Capacitance	C <sub>iss</sub>		$V_{CS} = 0$	1.	-	2322	-	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Output Capacitance	C <sub>oss</sub>		$V_{\rm DS} = 0.0$ V, $V_{\rm DS} = 100$ V,		-	105	-	1
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Reverse Transfer Capacitance		f = 1 MHz		-	4	-	pF	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		C <sub>o(er)</sub>	$V_{DS} = 0 V$ to 520 V, $V_{GS} = 0 V$		-	84	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $		C <sub>o(tr)</sub>			-	293	-		
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Total Gate Charge	Qg		V <sub>GS</sub> = 10 V I <sub>D</sub> = 11 A, V <sub>DS</sub> = 520 V		-	71	106	nC
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V			-	14	-	
Rise TimetrVDD = 520 V, ID = 11 A, VGS = 0.1 Q-3468nsTurn-Off Delay Time $t_{d(off)}$ $V_{GS} = 10 V, R_g = 9.1 Q$ -68102-4284Fall Time $t_f$ $r$ $r$ 4284-0.78- $\Omega$ Gate Input ResistanceRg $f = 1 MHz$ , open drain- $0.78$ - $\Omega$ Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode53ADiode Forward VoltageVsDTJ = 25 °C, Is = 11 A, VGS = 0 V-0.91.2VReverse Recovery Time $t_{rr}$ TJ = 25 °C, Is = 11 A, dl/dt = 100 A/µs, V_R = 25 V-160-nsConditionedIsTJ = 25 °C, Is = 12 A, dl/dt = 100 A/µs, V_R = 25 V-1.2- $\mu C$	Gate-Drain Charge					-	33	-	
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-On Delay Time	t <sub>d(on)</sub>		$V_{DD} = 520 \text{ V}, \text{ I}_{\text{D}} = 11 \text{ A}, \\ V_{\text{GS}} = 10 \text{ V}, \text{ R}_{\text{g}} = 9.1 \Omega$		-	22	44	- ns
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	Rise Time		V <sub>DD</sub> =			-	34	68	
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Turn-Off Delay Time	t <sub>d(off)</sub>	V <sub>GS</sub> :			-	68	102	
Drain-Source Body Diode CharacteristicsContinuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentIsMIsMTJ = 25 °C, Is = 11 A, VGS = 0 V-0.91.2VDiode Forward VoltageVSDTJ = 25 °C, Is = 11 A, VGS = 0 V-0.91.2VReverse Recovery TimetrrTJ = 25 °C, IF = IS = 11 A, dI/dt = 100 A/µs, VR = 25 V-1.60-ns	Fall Time		1		-	42	84	]	
Continuous Source-Drain Diode CurrentIsMOSFET symbol showing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentIsmIsmT_J = 25 °C, I_S = 11 A, V_{GS} = 0 V53-Diode Forward VoltageV_{SDT_J = 25 °C, I_S = 11 A, V_{GS} = 0 V-0.91.2VReverse Recovery TimetrrT_J = 25 °C, I_F = I_S = 11 A, dl/dt = 100 A/µs, V_R = 25 V-1.60-ns	Gate Input Resistance	Rg	f = 1 MHz, open drain		-	0.78	-	Ω	
Continuous Source-Drain Diode CurrentISshowing the integral reverse $p - n$ junction diode21APulsed Diode Forward CurrentISMISM $p - n$ junction diode5353Diode Forward VoltageVSDTJ = 25 °C, IS = 11 A, VGS = 0 V-0.91.2VReverse Recovery Time $t_{rr}$ TJ = 25 °C, IF = IS = 11 A, dl/dt = 100 A/µs, VR = 25 V-160-ns	Drain-Source Body Diode Characteristi	cs							
Pulsed Diode Forward CurrentIsmIntegral reverse p - n junction diode53Diode Forward Voltage $V_{SD}$ $T_J = 25 \ ^{\circ}C$ , $I_S = 11 \ A$ , $V_{GS} = 0 \ V$ -0.91.2VReverse Recovery Time $t_{rr}$ $T_J = 25 \ ^{\circ}C$ , $I_F = I_S = 11 \ A$ , dl/dt = 100 A/µs, $V_R = 25 \ V$ -160-nsTotal Control $T_J = 25 \ ^{\circ}C$ , $I_F = I_S = 11 \ A$ , dl/dt = 100 A/µs, $V_R = 25 \ V$ -1.2-µC	Continuous Source-Drain Diode Current	I <sub>S</sub>		- IB		-	-	21	
Reverse Recovery Time $t_{rr}$ $T_J = 25 \ ^{\circ}C$ , $I_F = I_S = 11 \ A$ , $dl/dt = 100 \ A/\mu s$ , $V_R = 25 \ V$ -160 \ -nsT_J = 25 \ ^{\circ}C, $I_F = I_S = 11 \ A$ , $dl/dt = 100 \ A/\mu s$ , $V_R = 25 \ V$ -1.2 \ - $\mu C$	Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	53	A	
Reverse Recovery Time $t_{rr}$ $T_J = 25 \ ^{\circ}C$ , $I_F = I_S = 11 \ A$ , $dl/dt = 100 \ A/\mu s$ , $V_R = 25 \ V$ -160 \ -nsT_J = 25 \ ^{\circ}C, $I_F = I_S = 11 \ A$ , $dl/dt = 100 \ A/\mu s$ , $V_R = 25 \ V$ -1.2 \ - $\mu C$	Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 11 A, V <sub>GS</sub> = 0 V		-	0.9	1.2	V	
Reverse Recovery Charge $Q_{rr}$ $T_J = 25 \ ^{\circ}C$ , $I_F = I_S = 11 \ A$ , $dl/dt = 100 \ A/\mu s$ , $V_R = 25 \ V$ $ 1.2 \  \mu C$	-					-	160	-	ns
	-				-		-		
					-		-		

Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

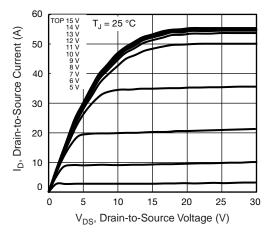


Fig. 1 - Typical Output Characteristics



Fig. 2 - Typical Output Characteristics

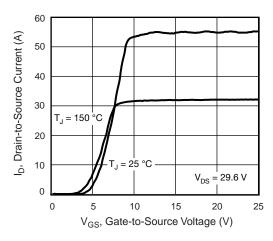


Fig. 3 - Typical Transfer Characteristics

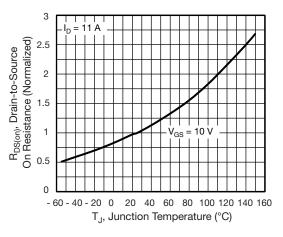


Fig. 4 - Normalized On-Resistance vs. Temperature

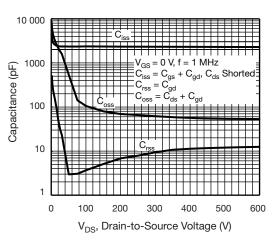


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

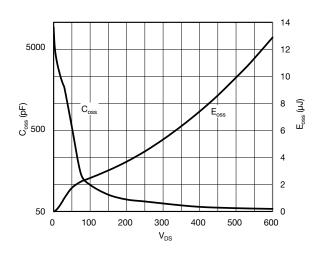


Fig. 6 -  $C_{oss}$  and  $E_{oss}$  vs.  $V_{DS}$ 

## IXTH30N60P-VB



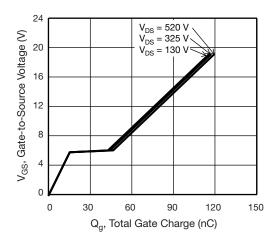


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

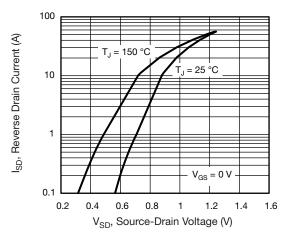


Fig. 8 - Typical Source-Drain Diode Forward Voltage

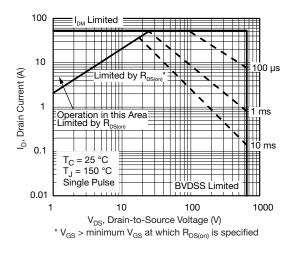


Fig. 9 - Maximum Safe Operating Area

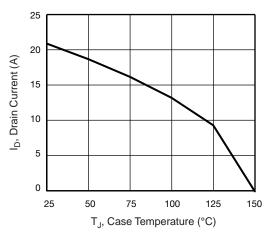


Fig. 10 - Maximum Drain Current vs. Case Temperature



Fig. 11 - Temperature vs. Drain-to-Source Voltage



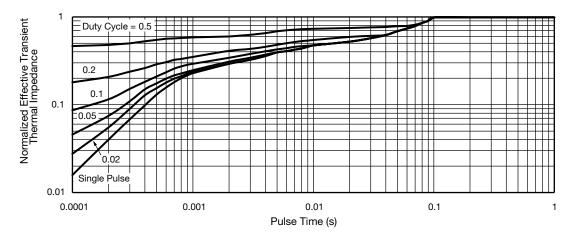


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case



Fig. 13 - Switching Time Test Circuit



Fig. 14 - Switching Time Waveforms

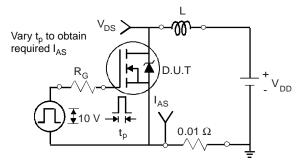


Fig. 15 - Unclamped Inductive Test Circuit

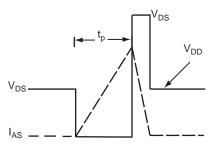


Fig. 16 - Unclamped Inductive Waveforms

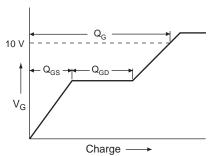
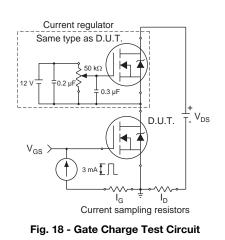
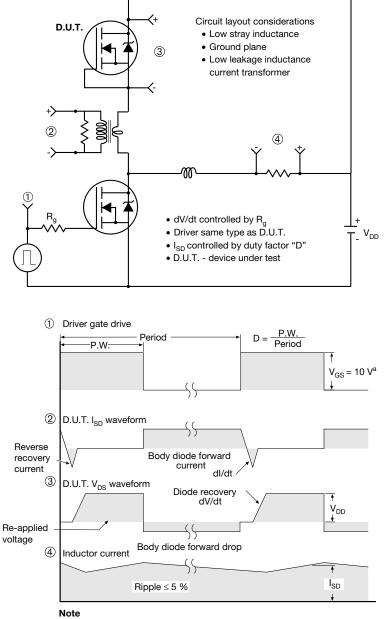


Fig. 17 - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit



a.  $V_{GS} = 5$  V for logic level devices

Fig. 19 - For N-Channel



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